

# Features vided by an active LOW Chip Enable (CE) and three-state driv-

- High speed
  - -15 ns
- · CMOS for optimum speed/power
- · Low active power
  - -495 mW
- · Low standby power
  - 220 mW
- TTL compatible inputs and outputs
- · Automatic power-down when deselected

#### **Functional Description**

The CY7C187 is a high-performance CMOS static RAM organized as 65,536 words x 1 bit. Easy memory expansion is pro-

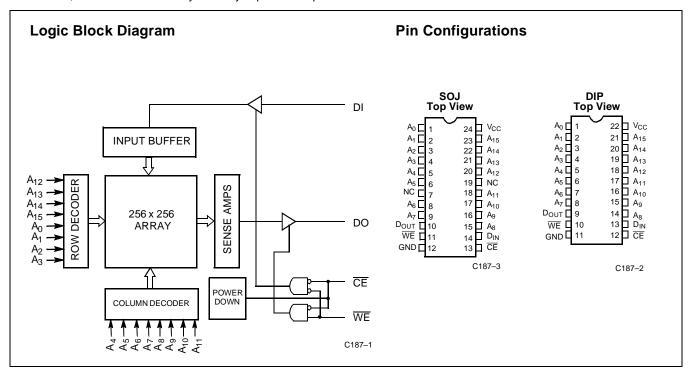
vided by an active LOW Chip Enable ( $\overline{\text{CE}}$ ) and three-state drivers. The CY7C187 has an automatic power-down feature, reducing the power consumption by 56% when deselected.

Writing to the device is accomplished when the Chip Enable  $(\overline{CE})$  and Write Enable  $(\overline{WE})$  inputs are both LOW. Data on the input pin  $(D_{IN})$  is written into the memory location specified on the address pins  $(A_0$  through  $A_{15}$ ).

Reading the device is accomplished by taking the Chip Enable  $(\overline{CE})$  LOW, while Write Enable  $(\overline{WE})$  remains HIGH. Under these conditions, the contents of the memory location specified on the address pin will appear on the data output  $(D_{OUT})$  pin.

The output pin stays in high-impedance state when Chip Enable  $(\overline{CE})$  is HIGH or Write Enable  $(\overline{WE})$  is LOW.

The CY7C187 utilizes a die coat to insure alpha immunity.



#### Selection Guide<sup>[1]</sup>

	7C187-15	7C187-20	7C187-25	7C187-35
Maximum Access Time (ns)	15	20	25	35
Maximum Operating Current (mA)	90	80	70	70
Maximum Standby Current (mA)	40/20	40/20	20/20	20/20

#### Note

1. For military specifications, see the CY7C187A datasheet.



## **Maximum Ratings**

(Above which the useful life may be impaired. For user guidelines, not tested.) Storage Temperature .....-65°C to +150°C Ambient Temperature with Power Applied ...... -55°C to +125°C Supply Voltage to Ground Potential (Pin 22 to Pin 11) ...... –0.5V to +7.0V DC Voltage Applied to Outputs in High Z State<sup>[2]</sup>.....-0.5V to +7.0V

DC Input Voltage <sup>[2]</sup>	0.5V to +7.0V
Output Current into Outputs (LOW)	20 mA
Static Discharge Voltage (per MIL–STD–883, Method 3015)	>2001V
Latch-Up Current	>200 mA

# **Operating Range**

Range	Ambient Temperature	v <sub>cc</sub>
Commercial	0°C to +70°C	5V ± 10%

## **Electrical Characteristics** Over the Operating Range

			7C187-15		7C18	37-20	7C187	'-25, 35	
Parameter	Description	Test Conditions	Min.	Max.	Min.	Max.	Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OH</sub> = -4.0 mA	2.4		2.4		2.4		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> =12.0 mA		0.4		0.4		0.4	V
V <sub>IH</sub>	Input HIGH Voltage		2.2	V <sub>CC</sub>	2.2	V <sub>CC</sub>	2.2	V <sub>CC</sub>	V
V <sub>IL</sub>	Input LOW Voltage <sup>[2]</sup>		-0.5	0.8	-0.5	0.8	-0.5	0.8	V
I <sub>IX</sub>	Input Load Current	$GND \leq V_I \leq V_CC$	-5	+5	-5	+5	<b>-</b> 5	+5	μΑ
I <sub>OZ</sub>	Output Leakage Current	$\begin{aligned} &\text{GND} \leq \text{V}_{O} \leq \text{V}_{CC}, \\ &\text{Output Disabled} \end{aligned}$	-5	+5	-5	+5	<b>-</b> 5	+5	μΑ
I <sub>OS</sub>	Output Short Circuit Current <sup>[3]</sup>	V <sub>CC</sub> = Max., V <sub>OUT</sub> = GND		-350		-350		-350	mA
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	V <sub>CC</sub> = Max., I <sub>OUT</sub> = 0 mA		90		80		70	mA
I <sub>SB1</sub>	Automatic CE Power- Down Current <sup>[4]</sup>	Max. V <sub>CC</sub> , CE ≥ V <sub>IH</sub>		40		40		20	mA
I <sub>SB2</sub>	Automatic CE Power-Down Current	$\begin{aligned} & \underbrace{\text{Max. V}_{\text{CC}}}, \\ & \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3\text{V}, \\ & \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3\text{V} \\ & \text{or V}_{\text{IN}} \leq 0.3\text{V} \end{aligned}$		20		20		20	mA

## Capacitance<sup>[5]</sup>

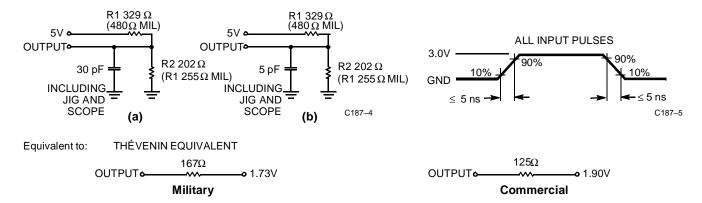
Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	10	pF
C <sub>OUT</sub>	Output Capacitance	$V_{CC} = 5.0V$	10	pF

#### Notes:

V<sub>IL</sub> (min.) = -3.0V for pulse durations less than 30 ns.
Not more than 1 output should be shorted at one time. Duration of the short circuit should not exceed 30 seconds.
A pull-up resistor to V<sub>CC</sub> on the CE input is required to keep the device deselected during V<sub>CC</sub> power-up, otherwise I<sub>SB</sub> will exceed values given.
Tested initially and after any design or process changes that may affect these parameters.



## **AC Test Loads and Waveforms**



## Switching Characteristics Over the Operating Range<sup>[6]</sup>

	7C187-15		87-15	7C1	87-20	
Parameter	Description	Min.	Max.	Min.	Max.	Unit
READ CYCLE			•	•	•	•
t <sub>RC</sub>	Read Cycle Time	15		20		ns
t <sub>AA</sub>	Address to Data Valid		15		20	ns
t <sub>OHA</sub>	Output Hold from Address Change	3		5		ns
t <sub>ACE</sub>	CE LOW to Data Valid		15		20	ns
t <sub>LZCE</sub>	CE LOW to Low Z <sup>[7]</sup>	3		5		ns
t <sub>HZCE</sub>	CE HIGH to High Z <sup>[7, 8]</sup>		8		8	ns
t <sub>PU</sub>	CE LOW to Power Up	0		0		ns
t <sub>PD</sub>	CE HIGH to Power Down		15		20	ns
WRITE CYCLE <sup>[9]</sup>		<u>.</u>				
t <sub>WC</sub>	Write Cycle Time	15		20		ns
t <sub>SCE</sub>	CE LOW to Write End	12		15		ns
t <sub>AW</sub>	Address Set-Up to Write End	12		15		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		ns
t <sub>PWE</sub>	WE Pulse Width	12		15		ns
t <sub>SD</sub>	Data Set-Up to Write End	10		10		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		ns
t <sub>LZWE</sub>	WE HIGH to Low Z	5		5		ns
t <sub>HZWE</sub>	WE LOW to High Z <sup>[8]</sup>		7		7	ns

#### Notes:

- 6.
- 7.
- Test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I<sub>OL</sub>/I<sub>OH</sub> and 30-pF load capacitance.

  At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub> for any given device.

  t<sub>HZCE</sub> and t<sub>HZWE</sub> are specified with C<sub>L</sub> = 5 pF as in part (b) of AC <u>Tes</u>t Loads. Transition is measured ±500 mV from steady-state voltage.

  The internal write time of the memory is defined by the overlap of CE LOW and WE LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.

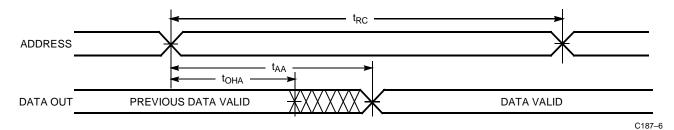


# Switching Characteristics Over the Operating Range<sup>[6]</sup> (continued)

	7C187-25 ameters Description Min. Max.		7C187-25		7C187-35	
Parameters			Max.	Min.	Max.	Units
READ CYCLE		•	•	•	•	
t <sub>RC</sub>	Read Cycle Time	25		35		ns
t <sub>AA</sub>	Address to Data Valid		25		35	ns
t <sub>OHA</sub>	Output Hold from Address Change	5		5		ns
t <sub>ACE</sub>	CE LOW to Data Valid		25		35	ns
t <sub>LZCE</sub>	CE LOW to Low Z <sup>[7]</sup>	5		5		ns
t <sub>HZCE</sub>	CE HIGH to High Z <sup>[7, 8]</sup>		10		15	ns
t <sub>PU</sub>	CE LOW to Power Up	0		0		ns
t <sub>PD</sub>	CE HIGH to Power Down		20		20	ns
WRITE CYCLE <sup>[9]</sup>						
t <sub>WC</sub>	Write Cycle Time	20		25		ns
t <sub>SCE</sub>	CE LOW to Write End	20		25		ns
t <sub>AW</sub>	Address Set-Up to Write End	20		25		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		ns
t <sub>PWE</sub>	WE Pulse Width	15		20		ns
t <sub>SD</sub>	Data Set-Up to Write End	10		15		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		ns
t <sub>LZWE</sub>	WE HIGH to Low	5		5		ns
t <sub>HZWE</sub>	WE LOW to High Z <sup>[8]</sup>		7		10	ns

# **Switching Waveforms**

Read Cycle No. 1<sup>[10, 11]</sup>



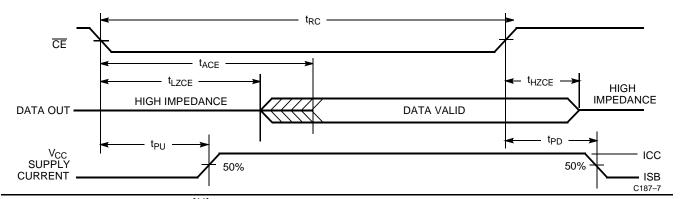
#### Notes:

10. WE is HIGH for read cycle.
11. Device is continuously selected, CE = V<sub>IL</sub>.

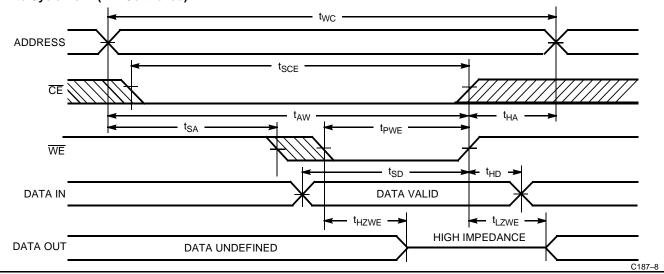


# **Switching Waveforms**

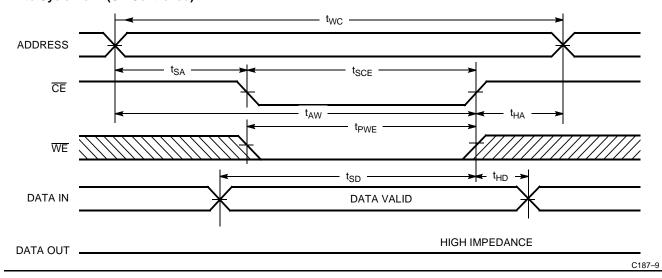
**Read Cycle No. 2**<sup>[10, 12]</sup>



# Write Cycle No. 1 (WE Controlled)[11]



# Write Cycle No. 2 ( $\overline{\text{CE}}$ Controlled)[11, 13]

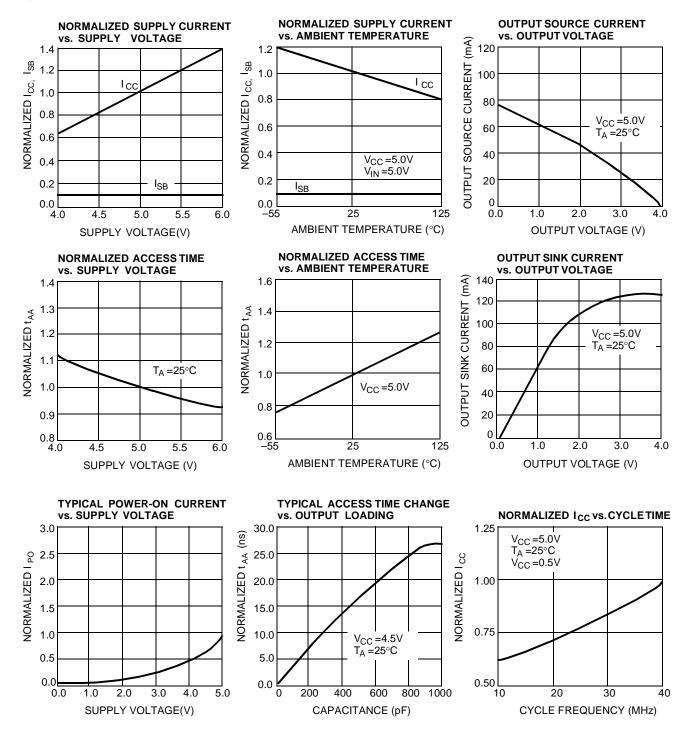


#### Notes:

- 12. Address valid prior to or coincident with CE transition LOW.
   13. If CE goes HIGH simultaneously with WE HIGH, the output remains in a high-impedance state.



## **Typical DC and AC Characteristics**





# **Address Designators**

Address Name	Address Function	Pin Number
A0	Х3	1
A1	X4	2
A2	X5	3
A3	X6	4
A4	X7	5
A5	Y7	6
A6	Y6	7
A7	Y2	8
A8	Y3	14
A9	Y1	15
A10	Y0	16
A11	Y4	17
A12	Y5	18
A13	X0	19
A14	X1	20
A15	X2	21

## **Truth Table**

CE	WE	Input/Output	Mode
Н	Χ	High Z	Deselect/Power-Down
L	Н	Data Out	Read
L	L	Data In	Write

# Ordering Information<sup>[14]</sup>

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
15	CY7C187-15PC	P9	22-Lead (300-Mil) Molded DIP	Commercial
	CY7C187-15VC	V13	24-Lead Molded SOJ	
20	CY7C187-20PC	P9	22-Lead (300-Mil) Molded DIP	Commercial
	CY7C187-20VC	V13	24-Lead Molded SOJ	
25	CY7C187-25PC	P9	22-Lead (300-Mil) Molded DIP	Commercial
	CY7C187-25VC	V13	24-Lead Molded SOJ	
35	CY7C187-35PC	P9	22-Lead (300-Mil) Molded DIP	Commercial
	CY7C187-35VC	V13	24-Lead Molded SOJ	

Note:

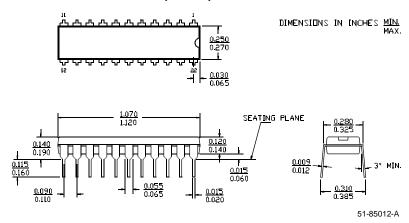
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<sup>14.</sup> For military variations, see the CY7C187A datasheet.

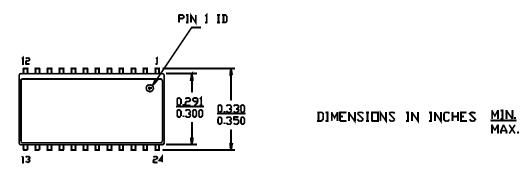


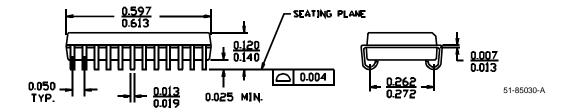
## **Package Diagrams**

#### 22-Lead (300-Mil) Molded DIP P9



#### 24-Lead (300-Mil) Molded SOJ V13





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